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With the principle of "Quality Parts, Customers Priority, Honest Operation, and Considerate Service", our business mainly focus on the distribution of electronic components. Line cards we deal with include Microchip, ALPS, ROHM, Xilinx, Pulse, ON, Everlight and Freescale. Main products comprise IC, Modules, Potentiometer, IC Socket, Relay, Connector. Our parts cover such applications as commercial, industrial, and automotives areas.

We are looking forward to setting up business relationship with you and hope to provide you with the best service and solution. Let us make a better world for our industry!



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Address: A1208, Overseas Decoration Building, #122 Zhenhua RD., Futian, Shenzhen, China









## **AUTOMOTIVE GRADE**

# AUIRF4104 AUIRF4104S

#### **Features**

- Advanced Process Technology
- Ultra Low On-Resistance
- 175°C Operating Temperature
- Fast Switching

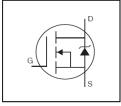
Description Specifically

- Fully Avalanche Rated
- Repetitive Avalanche Allowed up to Timax

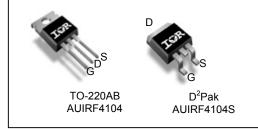
designed for Automotive applications,

HEXFET® Power MOSFET utilizes the latest processing

- Lead-Free, RoHS Compliant
- Automotive Qualified \*



V <sub>DSS</sub>	40V
R <sub>DS(on)</sub> typ.	4.3m $Ω$
max.	5.5mΩ
D (Silicon Limited)	120A⑨
D (Package Limited)	75A



•	G	D	S
	Gate	Drain	Source

techniques to achieve extremely low on-resistance per silicon area. Additional features of this design are a 175°C junction	AUIRF4104 AUIRF4104		
operating temperature, fast switching speed and improved repetitive avalanche rating. These features combine to make	G	D	s
this design an extremely efficient and reliable device for use in	Gate	Drain	Source
Automotive applications and wide variety of other applications.		•	

Base next number	Dookogo Typo	Standard Pack		Orderable Part Number
Base part number	Package Type	Form	Quantity	Orderable Part Number
AUIRF4104	TO-220	Tube	50	AUIRF4104
AUIRF4104S	D²-Pak	Tube	50	AUIRF4104S
AUIRF41045	D-Pak	Tape and Reel Left	800	AUIRF4104STRL

## **Absolute Maximum Ratings**

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only; and functional operation of the device at these or any other condition beyond those indicated in the specifications is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability. The thermal resistance and power dissipation ratings are measured under board mounted and still air conditions. Ambient temperature (TA) is 25°C, unless otherwise specified.

Symbol	Parameter	Max.	Units
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V (Silicon Limited)	1209	
I <sub>D</sub> @ T <sub>C</sub> = 100°C	Continuous Drain Current, V <sub>GS</sub> @ 10V (Silicon Limited)	849	1
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V (Wire Bond Limited)	75	A
I <sub>DM</sub>	Pulsed Drain Current ①	470	1
P <sub>D</sub> @T <sub>C</sub> = 25°C	Maximum Power Dissipation	140	W
	Linear Derating Factor	0.95	W/°C
$V_{GS}$	Gate-to-Source Voltage	± 20	V
E <sub>AS</sub>			
E <sub>AS</sub> (tested)	Single Pulse Avalanche Energy Tested Value ©	220	- mJ
I <sub>AR</sub>	Avalanche Current ①	See Fig.15,16, 12a, 12b	Α
E <sub>AR</sub>	Repetitive Avalanche Energy ®		mJ
TJ	Operating Junction and	-55 to + 175	
T <sub>STG</sub>	Storage Temperature Range		°C
	Soldering Temperature, for 10 seconds (1.6mm from case)	300	
	Mounting torque, 6-32 or M3 screw®	10 lbf•in (1.1N•m)	

### Thermal Resistance

Symbol	Parameter	Тур.	Max.	Units
$R_{\theta JC}$	Junction-to-Case ⑦		1.05	
$R_{\theta CS}$	Case-to-Sink, Flat, Greased Surface	0.50		°CAM
$R_{\theta JA}$	Junction-to-Ambient		62	°C/W
$R_{\theta JA}$	Junction-to-Ambient ( PCB Mount, steady state)		40	

HEXFET® is a registered trademark of Infineon.

<sup>\*</sup>Qualification standards can be found at www.infineon.com



# Static @ T<sub>J</sub> = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	40			V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient		0.032		V/°C	Reference to 25°C, I <sub>D</sub> = 1mA
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance		4.3	5.5	$m\Omega$	V <sub>GS</sub> = 10V, I <sub>D</sub> = 75A ③
$V_{GS(th)}$	Gate Threshold Voltage	2.0		4.0	٧	$V_{DS} = V_{GS}$ , $I_D = 250\mu A$
gfs	Forward Trans conductance	63			S	$V_{DS} = 10V, I_{D} = 75A$
1	Drain-to-Source Leakage Current			20		$V_{DS}$ =40V, $V_{GS}$ = 0V
I <sub>DSS</sub>	Dialii-10-Source Leakage Current			250	μA	$V_{DS} = 40V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
ı	Gate-to-Source Forward Leakage			200	- A	V <sub>GS</sub> = 20V
I <sub>GSS</sub>	Gate-to-Source Reverse Leakage			-200		V <sub>GS</sub> = -20V

## Dynamic Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

$Q_g$	Total Gate Charge	 68	100		I <sub>D</sub> = 75A
$Q_{gs}$	Gate-to-Source Charge	 21		nC	$V_{DS} = 32V$
$Q_{gd}$	Gate-to-Drain Charge	 27			V <sub>GS</sub> = 10V3
$t_{d(on)}$	Turn-On Delay Time	 16			$V_{DD} = 20V$
t <sub>r</sub>	Rise Time	 130		20	$I_D = 75A$
$t_{d(off)}$	Turn-Off Delay Time	 38		ns	$R_G = 6.8\Omega$
t <sub>f</sub>	Fall Time	 77			V <sub>GS</sub> = 10V ③
$L_D$	Internal Drain Inductance	 4.5		nH	Between lead, 6mm (0.25in.)
L <sub>S</sub>	Internal Source Inductance	 7.5		ПП	from package and center of die contact
C <sub>iss</sub>	Input Capacitance	 3000			V <sub>GS</sub> = 0V
C <sub>oss</sub>	Output Capacitance	 660			$V_{DS} = 25V$
C <sub>rss</sub>	Reverse Transfer Capacitance	 380		"F	f = 1.0MHz, See Fig. 5
C <sub>oss</sub>	Output Capacitance	 2160		pF	$V_{GS} = 0V, V_{DS} = 1.0V f = 1.0MHz$
C <sub>oss</sub>	Output Capacitance	 560			$V_{GS} = 0V, V_{DS} = 32V f = 1.0MHz$
Coss eff.	Effective Output Capacitance	 850			$V_{GS} = 0V, V_{DS} = 0V \text{ to } 32V  4$

#### **Diode Characteristics**

	Parameter	Min.	Тур.	Max.	Units	Conditions
I <sub>S</sub>	Continuous Source Current (Body Diode)			75	_	MOSFET symbol showing the
I <sub>SM</sub>	Pulsed Source Current (Body Diode) ①			470		integral reverse p-n junction diode.
$V_{SD}$	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C, I_S = 75A, V_{GS} = 0V$ ③
t <sub>rr</sub>	Reverse Recovery Time		23	35	ns	$T_J = 25^{\circ}C$ , $I_F = 75A$ , $V_{DD} = 20V$
$Q_{rr}$	Reverse Recovery Charge		6.8	10	nC	di/dt = 100A/µs ③
t <sub>on</sub>	Forward Turn-On Time	Intrinsio	Intrinsic turn-on time is negligible (turn-on is dominated by L <sub>S</sub> +L <sub>D</sub> )			

#### Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)
- ② Limited by  $T_{Jmax}$ , starting  $T_J$  = 25°C, L = 0.04mH,  $R_G$  = 25 $\Omega$ ,  $I_{AS}$  = 75A,  $V_{GS}$  =10V. Part not recommended for use above this value.
- Coss eff. is a fixed capacitance that gives the same charging time as Coss while VDS is rising from 0 to 80% VDSS.
- $\odot$  This value determined from sample failure population,  $T_J = 25^{\circ}C$ , L = 0.04mH,  $R_G = 25\Omega$ ,  $I_{AS} = 75$ A,  $V_{GS} = 10$ V.
- © This is applied to D<sup>2</sup>Pak When mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994
- $\ensuremath{\mathfrak{D}}$  R<sub>0</sub> is measured at T<sub>J</sub> of approximately 90°C
- This is only applied to TO-220AB package.
- © Calculated continuous current based on maximum allowable junction temperature. Bond wire current limit is 75A. Note that current limitations arising from heating of the device leads may occur with some lead mounting arrangements. (Refer to AN-1140)



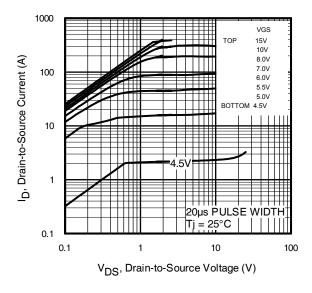


Fig. 1 Typical Output Characteristics

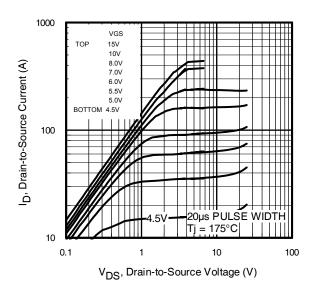


Fig. 2 Typical Output Characteristics

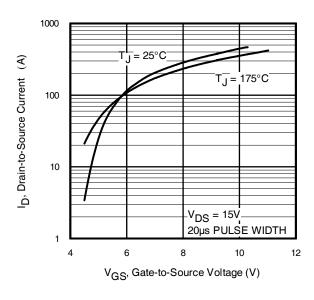
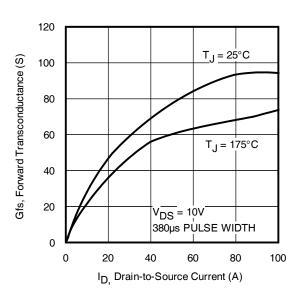
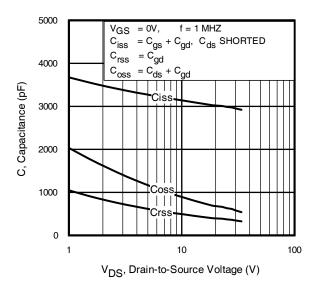


Fig. 3 Typical Transfer Characteristics

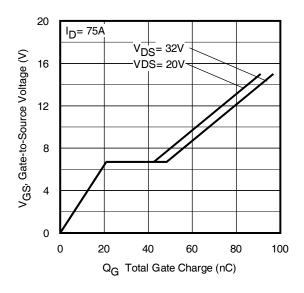


**Fig. 4** Typical Forward Transconductance vs. Drain Current





**Fig 5.** Typical Capacitance vs. Drain-to-Source Voltage



**Fig 6.** Typical Gate Charge vs. Gate-to-Source Voltage

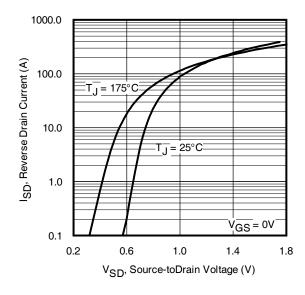


Fig. 7 Typical Source-to-Drain Diode Forward Voltage

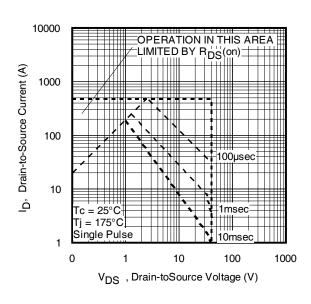
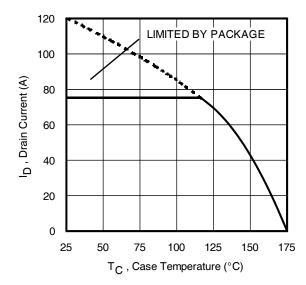


Fig 8. Maximum Safe Operating Area

4





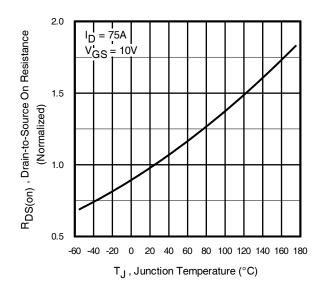


Fig 9. Maximum Drain Current vs. Case Temperature

**Fig 10.** Normalized On-Resistance vs. Temperature

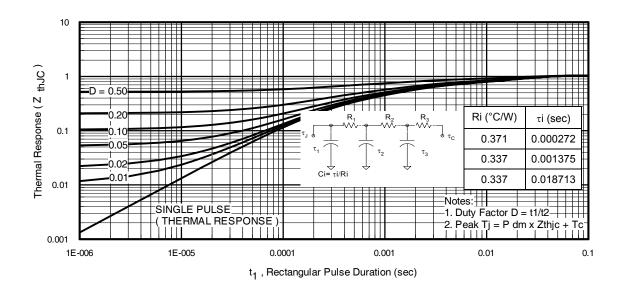


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case



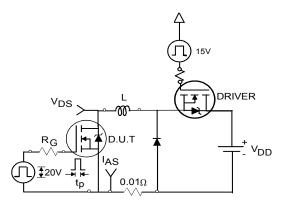


Fig 12a. Unclamped Inductive Test Circuit

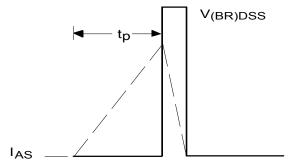


Fig 12b. Unclamped Inductive Waveforms

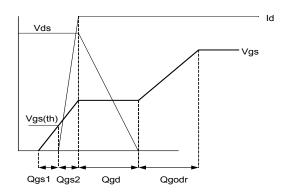


Fig 13a. Gate Charge Waveform

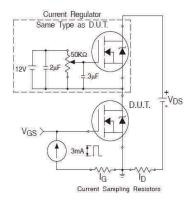


Fig 13b. Gate Charge Test Circuit

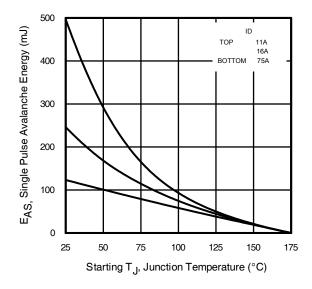


Fig 12c. Maximum Avalanche Energy vs. Drain Current

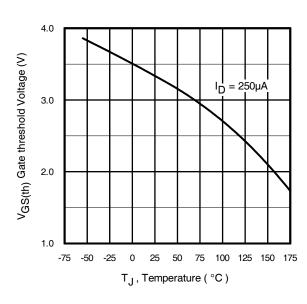


Fig 14. Threshold Voltage vs. Temperature



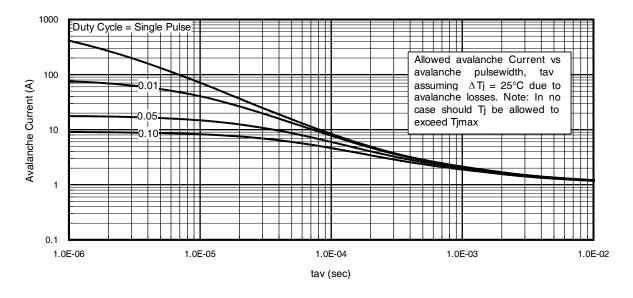
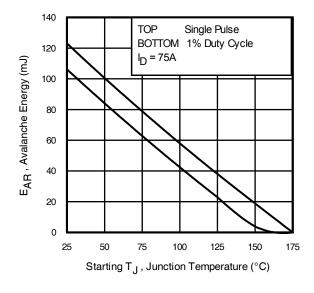


Fig 15. Typical Avalanche Current vs. Pulse width



**Fig 16.** Maximum Avalanche Energy vs. Temperature

Notes on Repetitive Avalanche Curves , Figures 15, 16: (For further info, see AN-1005 at www.infineon.com)

- Avalanche failures assumption:
   Purely a thermal phenomenon and failure occurs at a temperature far in
- excess of T<sub>jmax</sub>. This is validated for every part type. 2. Safe operation in Avalanche is allowed as long as T<sub>jmax</sub> is not exceeded.
- 3. Equation below based on circuit and waveforms shown in Figures 12a, 12b.
- 4. PD (ave) = Average power dissipation per single avalanche pulse.
- 5. BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
- 6. Iav = Allowable avalanche current.
- 7.  $\Delta T$  = Allowable rise in junction temperature, not to exceed  $T_{jmax}$  (assumed as 25°C in Figure 15, 16).

tav = Average time in avalanche.

D = Duty cycle in avalanche = tav ·f

ZthJC(D, tav) = Transient thermal resistance, see Figures 13)

$$\begin{split} P_{D \; (ave)} &= 1/2 \; (\; 1.3 \cdot BV \cdot I_{av}) = \Delta T / \; Z_{thJC} \\ I_{av} &= 2\Delta T / \; [1.3 \cdot BV \cdot Z_{th}] \\ E_{AS \; (AR)} &= P_{D \; (ave)} \cdot t_{av} \end{split}$$



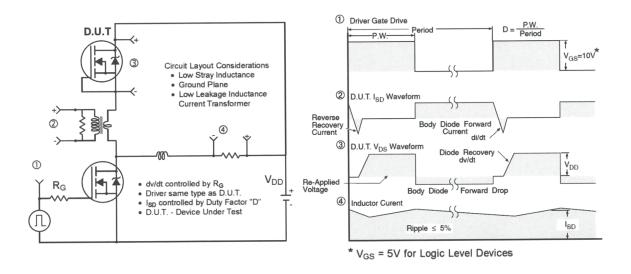


Fig 17. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

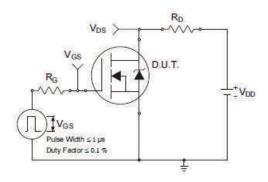


Fig 18a. Switching Time Test Circuit

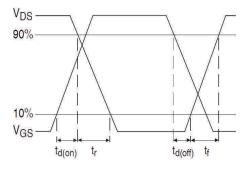
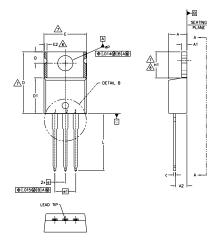
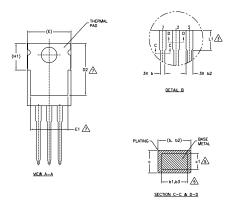


Fig 18b. Switching Time Waveforms



# TO-220AB Package Outline (Dimensions are shown in millimeters (inches))





#### NOTES:

- DIMENSIONING AND TOLERANCING AS PER ASME Y14.5 M- 1994.

- DIMENSIONING AND TOLERANGING AS PER ASME 114.5 M = 1994.

  DIMENSIONS ARE SHOWN IN INCHES [MILLIMETERS].

  LEAD DIMENSION AND FINISH UNCONTROLLED IN L1.

  DIMENSION D, D1 & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH

  SHALL NOT EXCEED .005" (0.127) PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.

DIMENSION 61, 63 & c1 APPLY TO BASE METAL ONLY.

- CONTROLLING DIMENSION: INCHES.
- THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSIONS E,H1,D2 & E1
- DIMENSION E2 X H1 DEFINE A ZONE WHERE STAMPING AND SINGULATION IRREGULARITIES ARE ALLOWED.
- OUTLINE CONFORMS TO JEDEC TO-220, EXCEPT A2 (max.) AND D2 (min.) WHERE DIMENSIONS ARE DERIVED FROM THE ACTUAL PACKAGE OUTLINE.

SYMBOL	MILLIMETERS		INC	HES	
	MIN.	MAX.	MIN.	MAX.	NOTES
Α	3.56	4.83	.140	.190	
A1	1.14	1.40	.045	.055	
A2	2.03	2.92	.080	.115	
b	0.38	1.01	.015	.040	
ь1	0.38	0.97	.015	.038	5
b2	1.14	1.78	.045	.070	
b3	1,14	1.73	.045	.068	5
c	0.36	0.61	.014	.024	
c1	0.36	0.56	.014	.022	5
D	14.22	16.51	.560	.650	4
D1	8.38	9.02	.330	.355	
D2	11.68	12.88	.460	.507	7
E	9.65	10.67	.380	.420	4,7
E1	6.86	8.89	.270	.350	7
E2	-	0.76	_	.030	8
e	2.54	2.54 BSC		BSC	
e1	5.08	BSC	.200	BSC	
H1	5.84	6.86	.230	.270	7,8
L	12.70	14.73	.500	.580	
L1	3.56	4.06	.140	.160	3
ØΡ	3.54	4.08	.139	.161	
Q	2.54	3.42	.100	.135	

#### LEAD ASSIGNMENTS

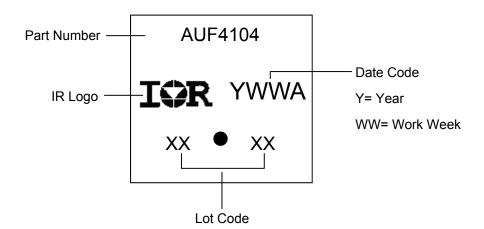
#### HEXFET

- 1.- GATE 2.- DRAIN 3.- SOURCE

#### IGBTs, CoPACK

- 1.- GATE 2.- COLLECTOR 3.- EMITTER
- DIODES
- 1.- ANODE 2.- CATHODE 3.- ANODE

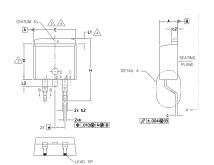
# **TO-220AB Part Marking Information**

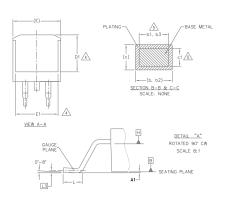


TO-220AB package is not recommended for Surface Mount Application.



# D<sup>2</sup>Pak (TO-263AB) Package Outline (Dimensions are shown in millimeters (inches))





- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].

AT THE OUTMOST EXTREMES OF THE PLASTIC BODY AT DATUM H.

4. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSION E, L1, D1 & E1.

5. DIMENSION 61, 63 AND c1 APPLY TO BASE METAL ONLY.

- 6. DATUM A & B TO BE DETERMINED AT DATUM PLANE H.
- 7. CONTROLLING DIMENSION: INCH.
- 8. OUTLINE CONFORMS TO JEDEC OUTLINE TO-263AB.

S Y M		DIMENSIONS					
В	MILLIMETERS		INC	HES	O T E S		
0 L	MIN.	MAX.	MIN.	MAX.	S E		
Α	4.06	4.83	.160	.190			
A1	0.00	0.254	.000	.010			
Ь	0.51	0.99	.020	.039			
ь1	0.51	0.89	.020	.035	5		
b2	1.14	1.78	.045	.070			
b3	1.14	1.73	.045	.068	5		
С	0.38	0.74	.015	.029			
с1	0.38	0.58	.015	.023	5		
c2	1.14	1.65	.045	.065			
D	8.38	9.65	.330	.380	3		
D1	6.86	_	.270	_	4		
E	9.65	10.67	.380	.420	3,4		
E1	6.22	-	.245	_	4		
е	2.54	BSC	.100	BSC			
Н	14.61	15.88	.575	.625			
L	1.78	2.79	.070	.110			
L1	_	1.68	_	.066	4		
L2	_	1.78	_	.070			
L3	0.25	BSC	.010	BSC			

#### LEAD ASSIGNMENTS

#### DIODES

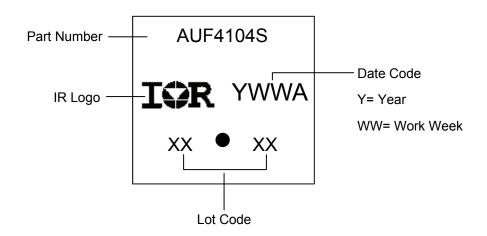
1.- ANODE (TWO DIE) / OPEN (ONE DIE)
2, 4.- CATHODE
3.- ANODE

## HEXFET

IGBTs, CoPACK 1.- GATE 2, 4.- DRAIN 3.- SOURCE

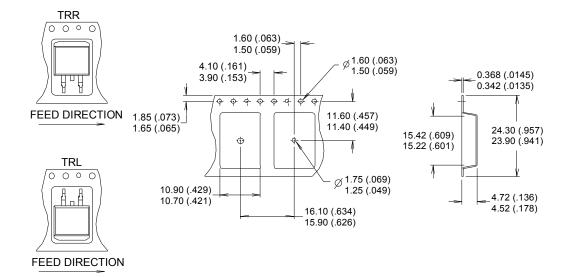
2, 4.- COLLECTOR 3.- EMITTER

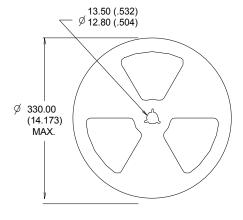
# D<sup>2</sup>Pak (TO-263AB) Part Marking Information





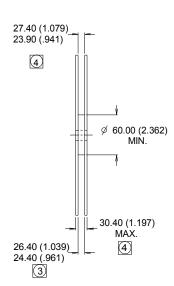
# D<sup>2</sup>Pak (TO-263AB) Tape & Reel Information (Dimensions are shown in millimeters (inches))







- COMFORMS TO EIA-418.
- 2. CONTROLLING DIMENSION: MILLIMETER.
- 3
- DIMENSION MEASURED @ HUB.
  INCLUDES FLANGE DISTORTION @ OUTER EDGE.





#### **Qualification Information**

qualification information							
			Automotive				
		(per AEC-Q101)					
		Comments: This part number(s) passed Automotive qualification. Infineon's Industrial and Consumer qualification level is granted by extension of the higher Automotive level.					
Moisture Sensitivity Level		TO-220AB	N/A				
Moistare	Moisture Sensitivity Level		MSL1				
	Machine Model	Class M4 <sup>†</sup>					
	Machine Wodei	AEC-Q101-002					
FOR	Lluman Dadu Madal	Class H1C <sup>†</sup>					
ESD	Human Body Model	AEC-Q101-001					
	Charried Davids Madel	Class C3 <sup>†</sup>					
Charged Device Model		AEC-Q101-005					
RoHS Compliant		Yes					

† Highest passing voltage.

# **Revision History**

Date	Comments
9/30/2015	Updated datasheet with corporate template
	Corrected ordering table on page 1.

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